

Atomic-level structure of a Ti-rich intergranular layer in BaTiO₃ ceramics revealed by STEM

Shijian Zheng^{1,2}, Rong Huang¹, Ku Du², Xiuliang Ma², Tsukasa Hirayama¹, Yuichi Ikuhara^{1,3}

¹Nanostructures Research Laboratory, Japan Fine Ceramics Center, Nagoya, 456-8587, Japan

²Shenyang National Laboratory for Materials Science, Institute of Metal Research, Chinese Academy of Sciences, Shenyang, 110016, China

³Institute of Engineering Innovation, The University of Tokyo, Tokyo, 113-8656, Japan

BaTiO₃-based ceramics are a model system for studying abnormal grain growth (AGG). For AGG to occur, excess Ti is required, and it is generally considered that the excess Ti bonds at grain boundaries (GBs) are a key to understanding the AGG behavior [1-4]. Unfortunately, the bonding at GBs in Ti-excess BaTiO₃-based ceramics is not well understood. Here we report the atomic-level structure of an intergranular layer in a BaTiO₃-based ceramic characterized by scanning transmission electron microscopy (STEM).

Er-doped Ti-excess BaTiO₃ (BaEr_{0.002}Ti_{1.004}O₃) was prepared by the conventional solid-state reaction method, with the final sintering performed at 1300°C for 10 h. A Cs-corrected JEM-2100F was used for HAADF-STEM imaging (detection angle range: 73-194 spatial mrad).

Abnormally-grown large grains with polyhedral shape were observed as shown in fig. 1(a), confirming that AGG occurred during sintering. After further TEM observation, it was found that both matrix GBs (boundaries between matrix grains, fig. 1(b)) and abnormal GBs (boundaries between abnormal grains and neighboring matrix grains, fig. 1(c)) were asymmetric with a (111) habit plane on one side of the boundary, which is a characteristic of GBs in AGG BaTiO₃-based ceramics [3-4]. Using HAADF-STEM, an intergranular layer was identified at such GBs. For example, in figure 1(d) the intergranular layer, which has an epitaxial relationship with the (111) plane of the abnormal grain, is clearly visible. It was also found that the intergranular layer continued to triple junctions, and at some triple junctions the intergranular phase transited completely into the Ti-rich Ba₄Ti₁₂O₂₇ phase. The intergranular layer can be described as a Ba₄Ti₁₂O₂₇-like phase with half the *a* lattice parameter of Ba₄Ti₁₂O₂₇. This is shown more clearly in fig. 1(e), which is an enlarged image of the dashed rectangle region in fig. 1(d). Model structures of BaTiO₃ [110] and Ba₄Ti₁₂O₂₇ [010] are superimposed on the image in accordance with the epitaxial relationship. Thus the GB layer can be seen to share a common Ti plane with the abnormal grain, indicated by a dashed line in Fig. 1(e). It is worth pointing out that the Ti-rich intergranular layer can accommodate the excess Ti and form at all the GBs with BaTiO₃ {111} habit planes. The intergranular layer should thus preferentially form GBs with {111} habit planes, which are necessary for AGG to occur.

This study clearly shows an intergranular layer with Ba₄Ti₁₂O₂₇-like structure at GBs with {111} habit planes in AGG BaTiO₃-based ceramics. Further investigations are being carried out.

References

[1] T. Yamamoto, Y. Ikuhara, K. Hayashi, T. Sakuma, *J. Mater. Res.* 13 (1998) 3449.

[2] B.K. Lee, S.Y. Chung, S. J. L. Kang, *Acta Mater.* 48 (2000) 1575.

[3] S.B. Lee, W. Sigle and M. Ruhle, *Acta Mater.* 50 (2002) 2151.

[4] S.J. Zheng, K. Du, X. H. Sang and X. L. Ma, *Phil. Mag.* 87 (2007) 5447.

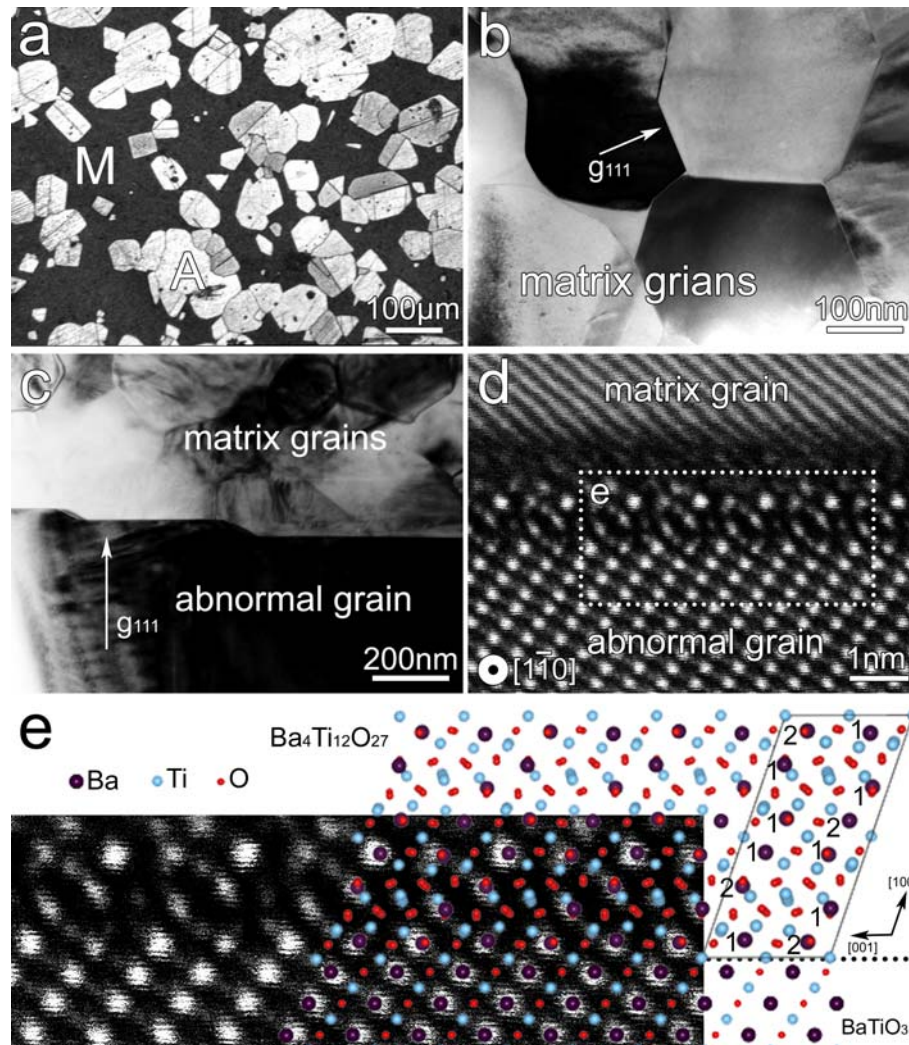


Figure 1: (a) an optical micrograph showing matrix and abnormal grains marked M and A respectively; (b) and (c) Bright-field images showing typical GBs with $\{111\}$ habit planes for a matrix GB and an abnormal GB respectively; (d) a typical HAADF-STEM image of an abnormal GB showing the intergranular layer; (e) an enlarged HAADF-STEM image of the dashed rectangle region superimposed with the model structure. In (e) a unit cell projection of $\text{Ba}_4\text{Ti}_{12}\text{O}_{27}$ is indicated by a gray line, two kinds of Ba columns with different atom densities in the projection direction are indicated by numbers 1 and 2. The shared Ti plane at the interface is indicated by a dashed line.